

**Search Notes**

Application/Control No.

10/647,913

Examiner

Sin J. Lee

Applicant(s)/Patent under  
Reexamination

YU ET AL.

Art Unit

1752

**SEARCHED**

Class	Subclass	Date	Examiner
430	270.1	6-8-05	STL
	300		
	302		
	944		
	905		
	911		
	910		
	271.1		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR